

عنوان مقاله:

Dynamic Strength Scaling for Delay Fault Propagation in Nanometer Technologies

محل انتشار:

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نویسندگان:

Reza Javaheri - Ryerson University/Department of Electrical and Computer Engineering, Toronto, Canada

Reza Sedaghat - Ryerson University/Department of Electrical and Computer Engineering, Toronto, Canada

خلاصه مقاله:

This paper proposes an algorithm for the detection of resistive delay faults in deep submicron technology using dynamic strength scaling, which is applicable for 45 nm and below. The approach uses an advanced coding system to build logical functions that are sensitive to strength and able to detect even the slightest voltage changes in the circuit.

Such changes are caused by interconnection resistive behavior and result in timing-related defects

کلمات کلیدی:

لینک ثابت مقاله در پایگاه سیویلیکا:

<https://civilica.com/doc/72990>

